


<b>Search Notes</b>  	<b>Application/Control No.</b>  10576220	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  MARCOS BATISTA	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
455	466	2/14/2008	mb
455	95	2/14/2008	mb

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with Steve D'Agosta	2/19/2008	mb
Consulted with TA - Yogesh Aggarwal	2/14/2008	mb
Consulted with Lun-YI Lao	2/19/2008	mb
East Search	2/14/2008	mb
Inventor's Name Seach	2/14/2008	mb
East Search	12/5/2008	mb
Consulted with Rafael Perez Gutierrez	12/4/2008	mb

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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